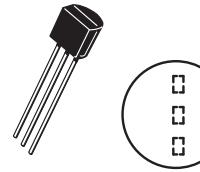
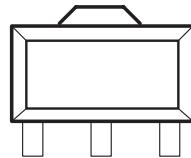




- Programmable Output Voltage to 36V
- Low Dynamic Output Impedance  $0.2\Omega$
- Sink Current Capability of 0.1 mA to 100 mA
- Equivalent Full-Range Temperature Coefficient of 50 ppm/ $^{\circ}\text{C}$
- Temperature Compensated for Operation over Full Rated Operating Temperature Range
- Low Output Noise Voltage
- Fast Turn on Response



**SOT-23**

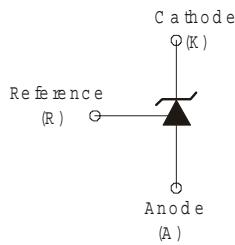


## DESCRIPTION

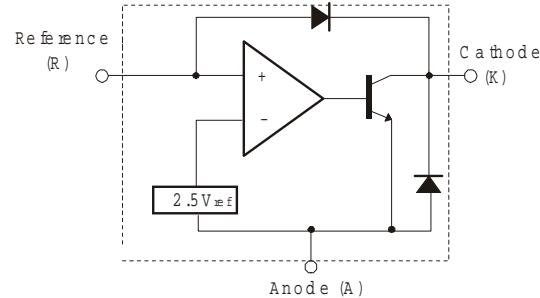
The TL431 is a three-terminal adjustable regulator series with a guaranteed thermal stability over applicable temperature ranges. The output voltage may be set to any value between  $\text{V}_{\text{ref}}$  (approximately 2.5 volts) and 36 volts with two external resistors. These devices have a typical dynamic output impedance of  $0.2\Omega$ . Active output circuitry provides a very sharp turn-on characteristic, making these devices excellent replacement for zener diodes in many applications.

The TL431 is characterized for operation from  $0^{\circ}\text{C}$  to  $+70^{\circ}\text{C}$ .

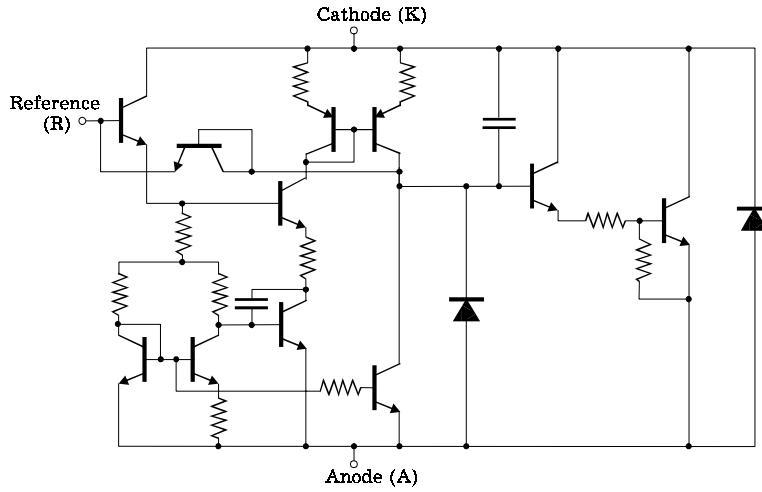
## SYMBOL



## FUNCTIONAL BLOCK DIAGRAM



## SCHEMATIC DIAGRAM



## ABSOLUTE MAXIMUM RATINGS

(Operating temperature range applies unless otherwise specified)

Characteristic	Symbol	Value	Unit
Cathode Voltage	V <sub>KA</sub>	37	V
Cathode Current Range (Continuous)	I <sub>K</sub>	-100 ~ +150	mA
Reference Input Current Range	I <sub>REF</sub>	0.05 ~ +10	mA
Operating Temperature Range	T <sub>a</sub>	0 ~ +70	°C
Storage Temperature Range	T <sub>stg</sub>	-65 ~ +150	°C

## RECOMMENDED OPERATING CONDITIONS

Characteristic	Symbol	Test Condition	Min	Typ	Max	Unit
Cathode Voltage	V <sub>KA</sub>	V <sub>REF</sub>		36		V
Cathode Current	I <sub>K</sub>		1.0		100	mA

## ELECTRICAL CHARACTERISTICS

(T<sub>a</sub> = 25°C, unless otherwise specified)

Characteristic	Symbol	Test Condition		Min	Typ	Max	Unit
Reference Input Voltage	V <sub>REF</sub>	V <sub>KA</sub> = V <sub>REF</sub> , I <sub>K</sub> = 10mA		2.44	2.495	2.55	V
Deviation of Reference Input Voltage Over-Temperature (Note 1)	V <sub>REF(dev)</sub>	V <sub>KA</sub> = V <sub>REF</sub> , I <sub>K</sub> = 10mA T <sub>min</sub> ≤ T <sub>a</sub> ≤ T <sub>max</sub>			4	17	mV
Ratio of Change in Reference Input Voltage to the Change in Cathode Voltage	$\frac{\Delta V_{REF}}{\Delta V_{KA}}$	I <sub>K</sub> = 10mA	ΔV <sub>KA</sub> = 10V-V <sub>REF</sub>		-1.4	-2.7	mV/V
			ΔK <sub>KA</sub> = 36V-10V		-1.0	-2.0	
Reference Input Current	I <sub>REF</sub>	I <sub>K</sub> = 10mA, R <sub>1</sub> = 10KΩ, R <sub>2</sub> = ∞			2,0	4	μA
Deviation of Reference Input Current Over Full Temperature Range	I <sub>REF(dev)</sub>	I <sub>K</sub> = 10mA, R <sub>1</sub> = 10KΩ, R <sub>2</sub> = ∞ T <sub>a</sub> = Full Range			0.4	1.2	μA
Minimum Cathode Current for Regulation	I <sub>K(min)</sub>	V <sub>KA</sub> = V <sub>REF</sub>			0.4	1.0	mA
Off-State Cathode Current	I <sub>K(off)</sub>	V <sub>KA</sub> = 36V, V <sub>REF</sub> = 0			0.1	1.0	μA
Dynamic Impedance (Note2)	Z <sub>KA</sub>	V <sub>KA</sub> = V <sub>REF</sub> , I <sub>K</sub> = 10mA to 100mA f ≤ 1.0KHz			0.2	0.5	Ω

Note: 1. The deviation parameters  $V_{REF(dev)}$  and  $I_{REF(dev)}$  are defined as the differences between the maximum and minimum values obtained over the rated temperature range.

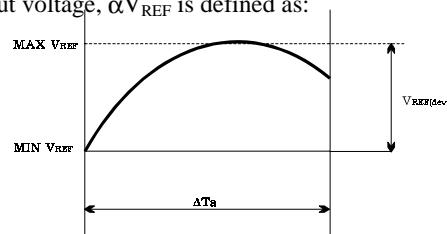
$$V_{REF(dev)} = V_{REF(max)} - V_{REF(min)}$$

The equivalent full-range temperature coefficient of the reference input voltage,  $\alpha V_{REF}$  is defined as:

$$\alpha V_{REF} \left( \frac{^{\circ}\text{C}}{\text{ppm}} \right) = \frac{\left( \frac{V_{REF(dev)}}{V_{REF@ \text{ } ^{\circ}\text{C}}} \right) \times 10^6}{\Delta T_a}$$

where  $\Delta T_a$  is the rated operating free-air temperature range of the device.

$\alpha V_{REF}$  can be positive or negative depending on whether minimum  $V_{REF}$  or maximum  $V_{REF}$  respectively, occurs at the lower temperature.



2. The dynamic impedance is defined as:

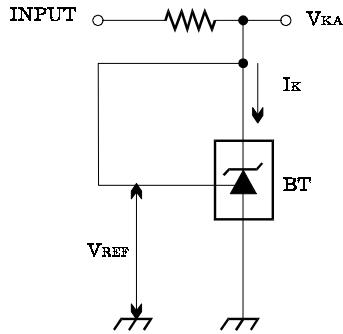
$$|Z_{KA}| = \frac{\Delta V_{KA}}{\Delta I_K}$$

When the device is operated with two external resistors (see Figure 2), the total dynamic impedance of the circuit is given by:

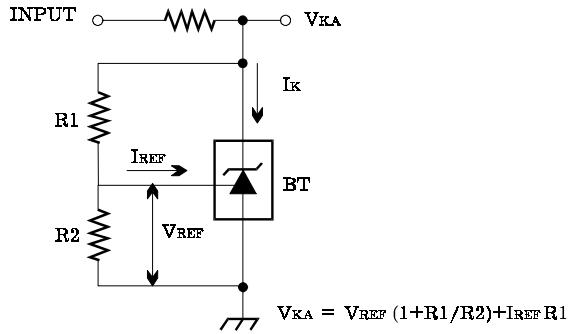
$$|Z| = \frac{\Delta V}{\Delta I} = |Z_{KA}| \left( 1 + \frac{R_1}{R_2} \right)$$

## TEST CIRCUITS

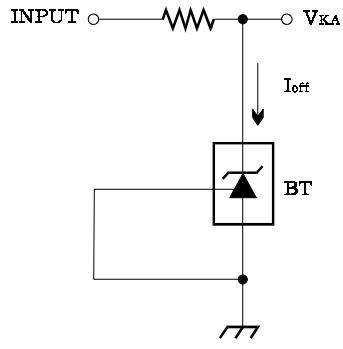
**Fig.1. Test Circuit for  $V_{KA} = V_{REF}$**



**Fig.2. Test Circuit for  $V_{KA} \geq V_{REF}$**

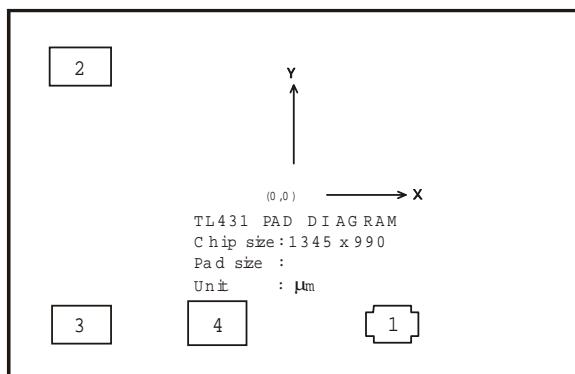


**Fig.3. Test Circuit for  $I_{off}$**



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## PAD LAYOUT



## PAD LOCATION

Unit: $\mu\text{m}$				
Pad No.	Pad Name	Description	X	Y
1	R	Reference	235	400
2	K	Cathode	-505	343.5
3	K	Cathode	-497.5	-346
4	A	Anode	-177.5	-341.5

Physical Characteristics		
Wafers	4 inch	$460 \pm 40 \mu\text{m}$ (thickness)
Size	$1.35 \times 0.99 \text{ mm}$	
Scribe width	90 $\mu\text{m}$	
Wafer's Backside	Ti – Ni – Ag: Ti - $0.1 \pm 0.02 \mu\text{m}$ Ni - $0.5 \pm 0.1 \mu\text{m}$ Ag - $0.6 \pm 0.1 \mu\text{m}$	
Passivation	PSG	